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(54) **CIRCUIT BOARD CONTACT PADS**

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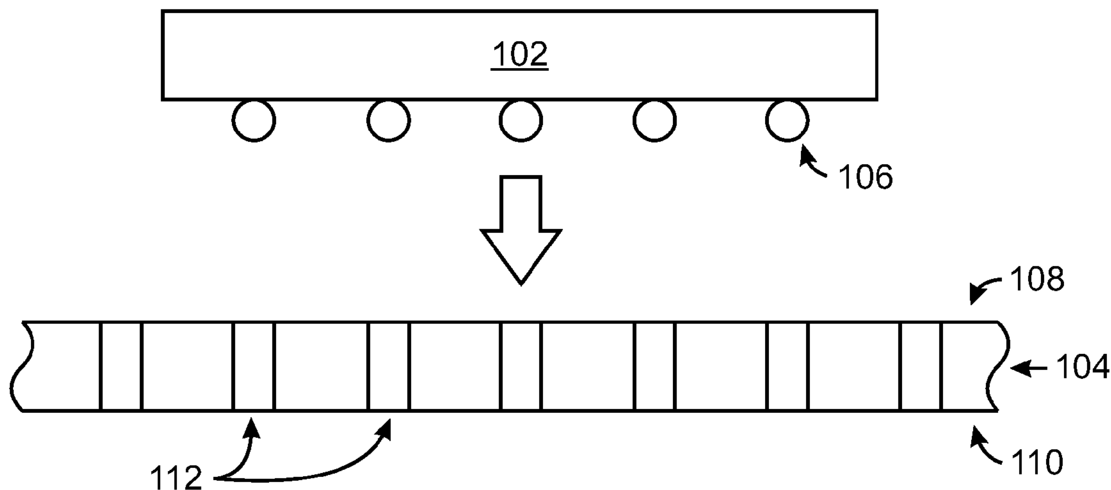
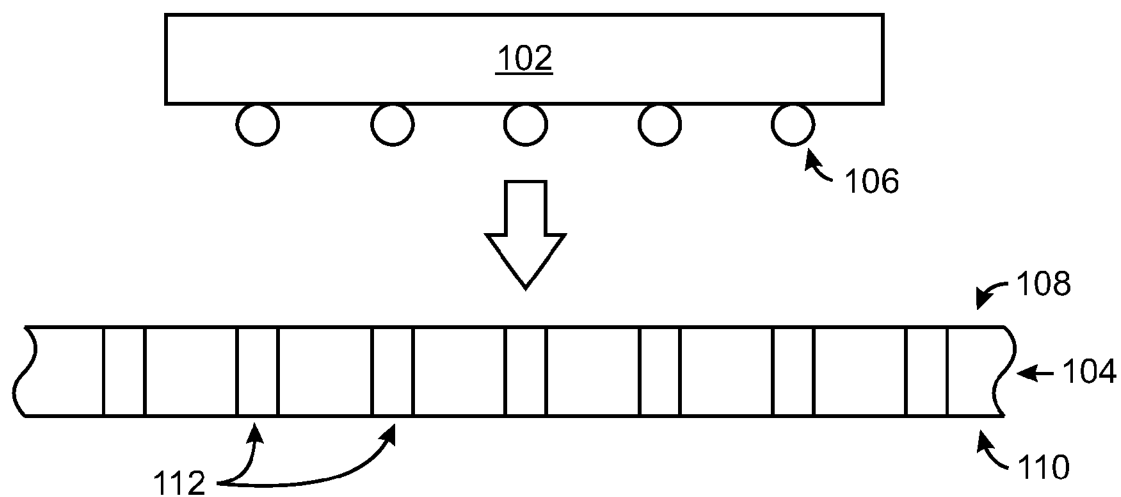
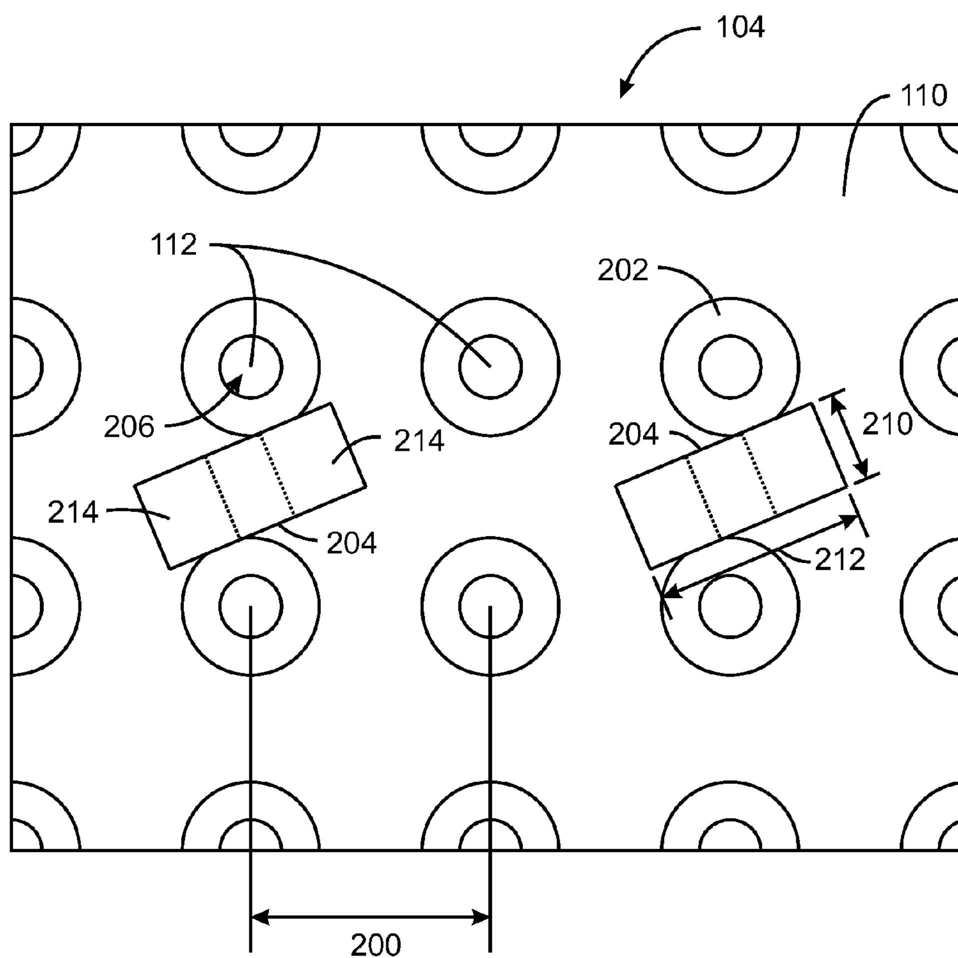
(57) **ABSTRACT**

The present disclosure provides a circuit board with a first via and a second via, the first and second vias providing an electrical path from a top surface of the circuit board to a bottom surface of the circuit board. The circuit board also includes a first contact pad electrically coupled to the first via and a second contact pad electrically coupled to the second via. The first contact pad is disposed at an angle with respect to a reference line crossing through the center of the first and second vias, and the second contact pad is disposed on an opposite side of the reference line at the angle with respect to the reference line, such that a footprint that encompasses an area between the first and second contact pads does not cover the first and second vias.





100
FIG. 1



200
FIG. 2

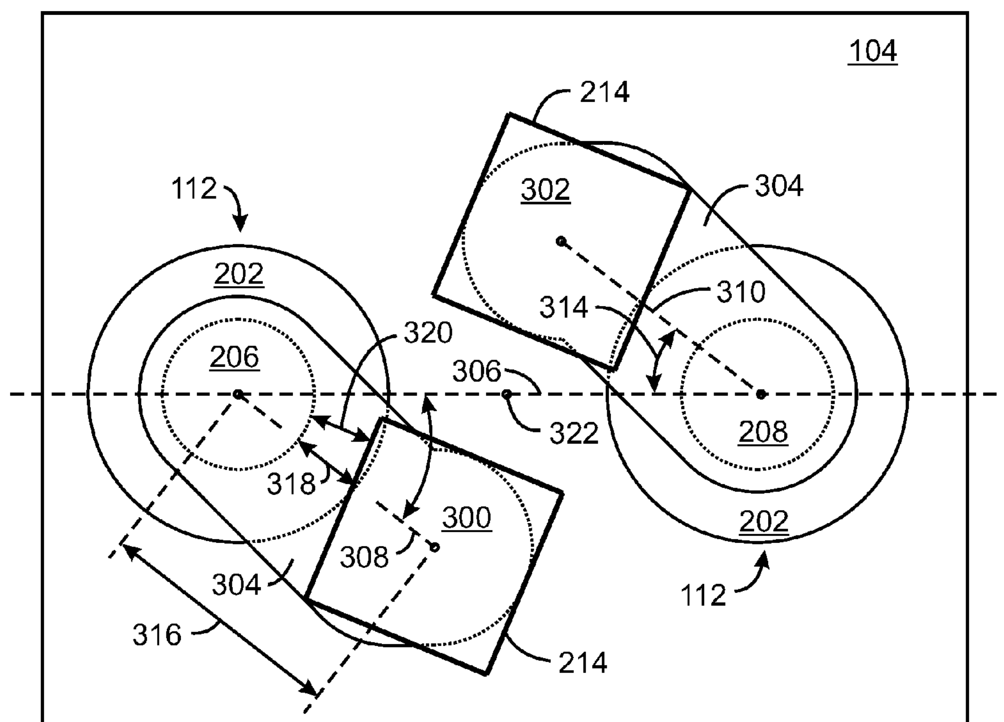


FIG. 3

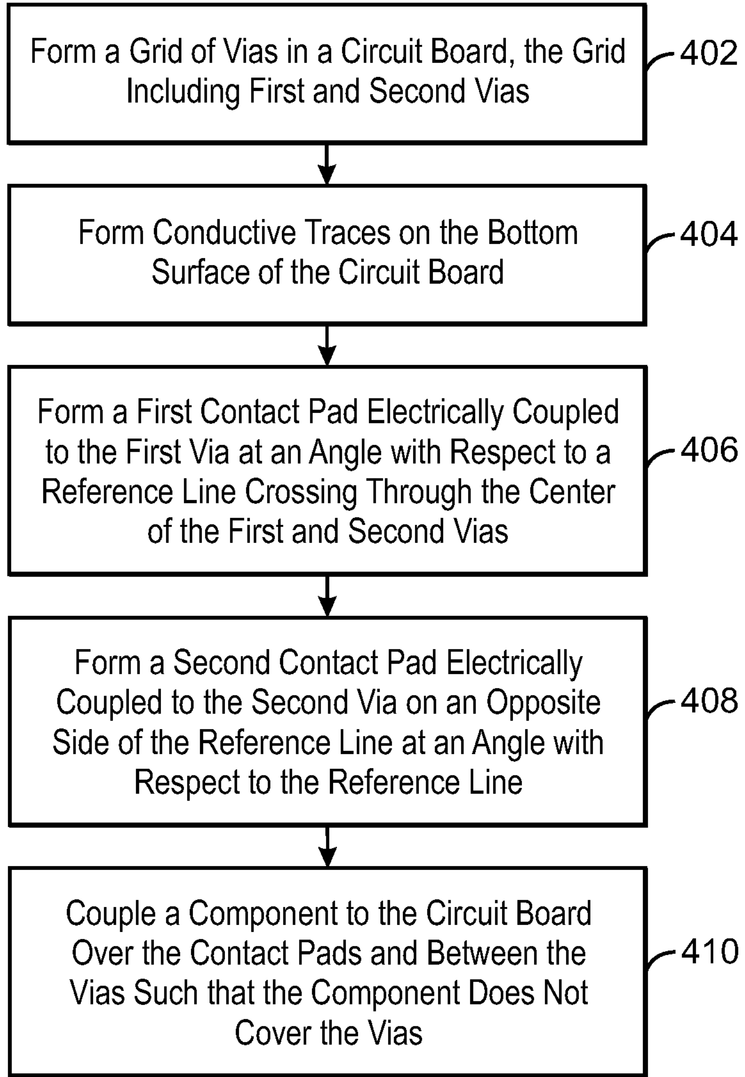


FIG. 4

CIRCUIT BOARD CONTACT PADS

BACKGROUND

[0001] Reducing the size of electronic devices presents various technical challenges. As computer chips become smaller, techniques for mounting those chips to circuit boards become increasingly complex. One technique that is often used for mounting chips to circuit boards is referred to as ball grid array, wherein solder balls are disposed on electrical contacts at the bottom of the chip. The solder balls are soldered to corresponding contact pads on the circuit board. The circuit board's contact pads may be electrically coupled to conductive through holes, referred to as vias, that provide routing of signals from the chip to other components mounted to the circuit board. Chips such as Application Specific Integrated circuits (ASICs) often include power and ground connections to the circuit board. Capacitors, often referred to as "bypass capacitors" or "decoupling capacitors," are usually coupled across the power and ground connections to filter out unwanted electrical noise that may be generated by the power supply. The bypass capacitors may be disposed on the bottom side of the circuit board within the footprint of the ASIC.

[0002] As chips such as ASICs grow in complexity, and shrink in size, the ball pitch grid pattern also shrinks. As the ball pitch grid patterns become smaller, less room is available on the circuit board for components such as bypass capacitors. One technique that has been developed to overcome this challenge is referred to as "Via in Pad," which enables the bypass capacitors to be disposed directly under the via, in other words, covering the via on the bottom side of the circuit board. However, the Via in Pad technique adds additional cost to the process of fabricating the circuit board. For example, Via in Pad typically use a via filling and plating process, referred to as Plated Over Filled Via (POFV), which introduces significant manufacturing cost for each circuit board.

BRIEF DESCRIPTION OF THE DRAWINGS

[0003] Certain embodiments are described in the following detailed description and in reference to the drawings, in which:

[0004] FIG. **1** is a side view of an electronic device in accordance with embodiments;

[0005] FIG. **2** is a bottom view of a portion of the circuit board, in accordance with embodiments;

[0006] FIG. **3** is a bottom view of a portion of the circuit board, in accordance with embodiments; and

[0007] FIG. **4** is a process flow diagram of a method of fabricating a circuit board, in accordance with embodiments.

DETAILED DESCRIPTION

[0008] Embodiments described herein relate to an improved component layout for a circuit board. The component layout in accordance with embodiments uses smaller components, which are spaced away from the vias and rotated to fit within the available area between the vias. This new component layout enables the elimination of the Plated Over Filled Via (POFV) process, resulting in significant cost savings. In embodiments, the improved component layout is used to place bypass capacitors on the bottom side of a circuit board, which is configured to receive an Application Specific Integrated Circuit (ASIC). Previous generations of ASICs had a 1.0 mm grid array which allowed for traces to be routed between the pads and vias. However, newer generations of ASICs use a 0.8 mm, or smaller, grid array, which significantly reduces the amount of area available for routing and component placement between the vias.

[0009] FIG. **1** is a side view of an electronic device in accordance with embodiments. The electronic device **100** may be any suitable device, such as a general purpose computer, server, notebook computer, workstation, mobile phone, smart phone, tablet PC, or digital camera, among others. The electronic device **100** includes a circuit chip **102** mounted to a circuit board **104**. It will be appreciated that the electronic device **100** includes many other circuits and components, which, for the sake of clarity, are not shown in FIG. **1**. Further, the circuit board **104** and circuit chip **102** are not drawn to scale.

[0010] The circuit chip **102** may be any suitable type of circuit chip, such as an Application Specific Integrated Circuit (ASIC), field-programmable gate array (FPGA), general purpose microprocessor, or any SMT (Surface-Mount Technology) device that involves the placement of passive components within the BGA array. The circuit chip **102** may be electrically coupled to the circuit board **104** using a surface mount packaging technique known as "ball grid array," which uses an array of solder balls **106** disposed on a bottom surface of the circuit chip. The circuit board **104** may be a printed circuit board (PCB) or any other suitable type of circuit board. The circuit board **104** includes a top surface **108** and a bottom surface **110**. The top surface **108** of the circuit board **104** refers to the surface to which the circuit chip **102** is mounted, and the bottom surface **110** refers to the surface opposite the top surface **108**. An array of contact pads (not shown) may be disposed on the top surface **108** of the circuit board **104** in a pattern that matches the array of solder balls **106**. The solder balls **106** of the circuit chip **102** are placed in contact with the array of conductive pads and heated to form a conductive bond. The circuit board **104** also includes conductive traces for coupling components of the circuit chip **102** to other components mounted to the circuit board **104**.

[0011] The circuit board **104** also includes vias **112** that form a conductive path from the top surface **108** of the circuit board **108** to the bottom surface **110** of the circuit board **104**. The circuit board **104** also includes components that are mounted to the bottom surface **110** of the circuit board **104** directly below the circuit chip **102**. The vias **112** enable components mounted to the bottom surface **110** of the circuit board **104** to be electrically coupled to the circuit chip **102**, including thermal relief, and signal, power and ground distribution.

[0012] FIG. **2** is a bottom view of a portion of the circuit board, in accordance with embodiments. Each of the vias **112** forms a through hole that connects the top surface (not shown) of the circuit board **104** with the bottom surface **110** of the circuit board **104**. As used herein, the term "via pitch" refers to the center-to-center distance **200** between the vias **112**. In embodiments, the via pitch is approximately 0.8 millimeters. However, embodiments of the present techniques may be implemented in circuit boards **104** with any suitable via pitch, including via pitch of 1.0 millimeters or more. Each via **112** may include a conductive layer formed on the walls of the via **112** to provide the conductive path through the via **112**. In embodiments, the vias **112** are plugged to prevent solder from wicking through the via **112** during subsequent soldering operations. Each via **112** may be electrically coupled to a conductive pad, referred to herein as a via pad **202**, which surrounds the via **112** and is electrically coupled

to the conductive material within the via **112**. The via pad **202** provides a conductive contact that enables other electrical components to be coupled to the circuit chip **102** (FIG. **1**) through the via **112**.

[0013] Some of the vias **112** may be coupled to electrical components, such as bypass capacitors **204**, which are mounted to the bottom surface **110** of the circuit board **104**. For example, some of the vias **112** may be power vias **206** and ground vias **208**, which are vias configured to couple a power source to the circuit chip **102**. As explained above, the bypass capacitors **204** are coupled across each power via **206** and its corresponding ground via **208** to filter out noise generated by the power source. The bypass capacitors **204** can also serve to dampen noise generated by the circuit chip **102** itself. For the sake of clarity, the bypass capacitors **204** are shown in transparent view. As an example, FIG. **2** shows two power vias **206**, each power via associated with a corresponding ground via **208**. However, it will be appreciated that the circuit board **104** can include any suitable number of power vias **206** and ground vias **208**, depending on the configuration of the circuit chip **102**. Furthermore, bypass capacitors **204** are only one example of a passive component that can be mounted on the bottom surface **110** of the circuit board **104** in accordance with embodiments. Other examples of components that can be mounted on the bottom surface **110** of the circuit board **104** include inductors and resistors.

[0014] As shown in FIG. **2**, the bypass capacitors **204** are disposed between power via **206** and the corresponding ground via **208** such that they do not overlap the vias **112**. Because the bypass capacitors do not overlap the vias **112**, there is no risk of solder wicking through the vias **112** during the process of soldering the bypass capacitors **204** into place. As explained above, this enables the process of fabricating the vias **112** to be simplified, because the typical Plated Over Filled Via (POFV) process can be eliminated. The footprint of the bypass capacitors **204** will depend, in part, on the available surface area that exists between the vias **112**. For example, depending on the via pitch, the width **210** of each bypass capacitor **204** may be approximately 10 mils (thousandths of an inch) and the length **212** of each bypass capacitor **204** may be approximately 20 mils. However, larger or smaller components may be placed between the vias **112** in accordance with embodiments, depending on the available area between the vias **112**.

[0015] To facilitate the mounting and electrical coupling of the bypass capacitors **204**, the power vias **206** and ground vias **208** may be electrically coupled to corresponding contact pads **214** disposed on the bottom surface **110** of the circuit board **104**. Each bypass capacitor **204** includes corresponding contacts and is mounted over the surface of the contact pads **214**. The configuration of the contact pads **214** is described further below in relation to FIG. **3**.

[0016] FIG. **3** is a bottom view of a portion of the circuit board, in accordance with embodiments. Specifically, FIG. **3** shows a close-up view of an example of a bypass capacitor **204** disposed between a power via **206** and a ground via **208**. The contact pad **114** coupled to the power via **206** may be referred herein as the power pad **300**, and the contact pad **214** coupled to the ground via **208** may be referred to herein as the ground pad **302**. Each of the contact pads **214** may be coupled to its respective via **112** by a conductive trace etch **304**. In embodiments, each of the contact pads **214** is approximately 12 mils by 12 mils. The positions of the contact pads **214** are described in relation to three reference lines. A first reference line **306** crosses through the center of the power via **206** and the ground via **208**. A second reference line **308** passes through the center of the power via **206** and the center of the power pad **300**. A third reference line **310** passes through the center of the ground via **208** and the center of the ground pad **302**.

[0017] As shown in FIG. **3**, each contact pad **214** is disposed at an angle with respect to the first reference line **306**, and the contact pads **214** are disposed on opposite sides of the first reference line **306**. More specifically, the first reference line **306** and the second reference line **308** define a first angle **312**, and the first reference line **306** and the third reference line **310** define a second angle **314** extending from the opposite side of the first reference line **306**. In embodiments, the first angle **312** and the second angle **314** are approximately equal and both may be referred to as the placement angle. It will be appreciated that as the placement angle increases, the distance between the contact pads **214** increases and the size of the bypass capacitor **204** (FIG. **2**) can also increase. Because the size of the bypass capacitor **204** determines its capacitance, the electrical characteristics of the bypass capacitor **204** can be adjusted to fit the desired electrical characteristics of a particular implementation by adjusting the placement angle. In embodiments, the placement angle is in a range from 0 degrees to 180 degrees, or from 30 degrees to 90 degrees, or any other suitable range. In embodiments, the placement angle may be approximately 67.5 degrees. In embodiments, the value of the placement angle will be such that a footprint that encompasses the power pad **300**, the ground pad **302**, and the area between the pads does not cover any portion of the vias **112**.

[0018] As the bypass capacitor **204** is moved away from the vias **112**, the inductance of the trace etch **304** will tend to reduce the effectiveness of the bypass capacitor **204**. Therefore, the distance between the contact pads **214** and their respective vias **112** is, in some embodiments, kept as short as possible. In embodiments, the distance **316** from the center of the contact pad **214** to the center of its respective via **112**, referred to herein as the placement distance, may be approximately 10 to 20 mils. In the example shown in FIG. **3**, the distance **316** from the center of the contact pad **214** to the center of its respective via **112** is approximately 14.86 mils. In embodiments, the edge of the contact pad **214** may slightly overlap the edge of the corresponding via pad **202**. In the example shown in FIG. **3**, the radial extent of the via pad **202** away from the edge of the via **112**, shown by the arrow **318**, is approximately 4.5 mils, and the shortest distance from the edge of the via **112** to the edge of the contact pad **214**, shown by the arrow **320**, is approximately 4.0 mils, resulting in approximately 0.5 mils of overlap. In embodiments, the relative positioning of the power pad **300** in relation to the power via **206** is the same as the relative positioning of the ground pad **302** in relation to the ground via **208**. In other words, the combination of the power via **206** and the power pad **300** will have the same outline as the combination of the ground via **208** and the ground pad **302** if rotated 180 degrees about the center point **322** between the power via **206** and the ground via **208**.

[0019] The contact pad placement described above enables the placement of a component between the vias **112** that does not cover the vias **112**. It will be appreciated that the specific dimensions provided herein are meant to provide context for a better understanding of the present techniques and are not meant to be limiting. Indeed, various other placement dis-

tances and angles may be used in accordance with embodiments depending on the specifications of a specific embodiment, such as the via pitch. The specific placement distances and angles may also be adjusted to provide suitable signal integrity, depending on the type and specifications of the component disposed between the vias **112**. Furthermore, although the layout described herein may be useful for fabricating a circuit board that has a small via pitch (for example, 0.8 millimeters or less) the present techniques may also be used in a circuit board with larger via pitches (for example, 1.0 millimeter or more.)

[0020] FIG. **4** is a process flow diagram of a method of fabricating a circuit board, in accordance with embodiments. The method may begin at block **402** wherein a grid of vias is formed in a circuit board. The grid of vias includes at a first via, which may be a power via, and a second via, which may be the corresponding ground via. The power via and ground via are configured to couple a circuit chip to a power supply. During the formation of the vias a conductive material may be disposed on the walls of the via. The conductive material may also extend over the bottom surface of the circuit board to form a via pad that enables electrical contact with the via.

[0021] At block **404**, conductive traces are formed on the bottom surface of the circuit board. The conductive traces provide electrical coupling between the vias and the contact pads that are formed at blocks **406** and **408**.

[0022] At block **406** a first contact pad is formed on the bottom surface of the circuit board and electrically coupled to the first via. As described above, the first contact pad may be formed at an angle with respect to a reference line crossing through the center of the first via and second via. In embodiments, the first contact pad is formed as close as possible to the via pad surrounding the first via. In embodiments, the first contact pad may slightly overlap the via pad of the first via.

[0023] At block **408**, a second contact pad is formed on the bottom surface of the circuit board and electrically coupled to the second via. As described above, the second contact pad may be formed at an angle with respect to the reference line crossing through the center of the first via and the second via. Further, the second contact pad is formed on the opposite side of the reference line compared to the first contact pad, forming juxtaposed contact pads over which an electrical component can be disposed between the vias without covering the vias. As with the first contact pad, the second contact pad may be formed as close as possible to the via pad surrounding the second via. In embodiments, the second contact pad may slightly overlap the via pad of the second via. The placement distance and angle of both contact pads is such that the footprint that encompasses an area between the first and second contact pads does not cover any portion of the first via or the second via.

[0024] At block **410**, a component such as a bypass capacitor may be coupled to the circuit board over the contact pads, such as by soldering contacts of the component to the contact pads. The positioning of the contact pads prevents the component coupled to the contact pads from covering the vias. Although embodiments are described in reference to coupling a bypass capacitor across a power via and a ground via, it will be appreciated that embodiments described herein are not limited to techniques for mounting bypass capacitors, and that the component may be any component that can be suitably mounted to the circuit board.

[0025] While the present techniques may be susceptible to various modifications and alternative forms, the exemplary embodiments discussed above have been shown only by way of example. It should be understood that the technique is not intended to be limited to the particular embodiments disclosed herein. Indeed, the present techniques include all alternatives, modifications, and equivalents falling within the true spirit and scope of the appended claims.

What is claimed is:

1. A circuit board, comprising:

a first via and a second via, the first and second vias providing an electrical path from a top surface of the circuit board to a bottom surface of the circuit board;

a first contact pad electrically coupled to the first via and a second contact pad electrically coupled to the second via;

wherein the first contact pad is disposed at a first angle with respect to a reference line crossing through the center of the first and second vias, and the second contact pad is disposed on an opposite side of the reference line at a second angle with respect to the reference line; and

wherein a footprint that encompasses an area between the first and second contact pads does not cover the first and second vias.

2. The circuit board of claim **1**, comprising a via pad disposed on the bottom surface of the circuit board around the via, wherein the first contact pad overlaps a portion of the via pad.

3. The circuit board of claim **1**, wherein a distance between the center of the first via and a center of the first contact pad is approximately 10 to 20 mils.

4. The circuit board of claim **1**, wherein a distance between the center of the first via and a center of the first contact pad is approximately 14.86 mils.

5. The circuit board of claim **1**, wherein the first angle and the second angle are approximately equal and are approximately 30 to 90 degrees.

6. The circuit board of claim **1**, wherein the first angle and the second angle are both approximately 67.5 degrees.

7. The circuit board of claim **1**, comprising an electrical component disposed over and electrically coupled to the first and second contact pads, wherein the component does not overlap the vias.

8. The circuit board of claim **7**, wherein the electrical component is disposed between the first and second vias.

9. The circuit board of claim **7**, wherein the first via is coupled to a power supply, the second via is coupled to ground, and the component is a bypass capacitor.

10. An electronic device, comprising:

a circuit chip mounted to a circuit board, the circuit board comprising:

a first via and a second via, the first and second vias providing an electrical path from a top surface of the circuit board to a bottom surface of the circuit board;

a first contact pad electrically coupled to the first via and a second contact pad electrically coupled to the second via;

wherein the first contact pad is disposed at a first angle with respect to a reference line crossing through the center of the first and second vias, and the second contact pad is disposed on an opposite side of the reference line at a second angle with respect to the reference line; and

wherein a footprint that encompasses an area between the first and second contact pads does not cover the first and second vias.

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11. The electronic device of claim **10**, wherein a center-to-center distance between the first and second vias is equal to or less than 0.8 millimeters and the electrical component is disposed between the first and second vias.

12. The electronic device of claim **10**, wherein a distance between the center of the first via and a center of the first contact pad is approximately 10 to 20 mils.

13. The electronic device of claim **10**, wherein the first angle and the second angle are approximately equal and in a range from approximately 30 to 90 degrees.

14. The electronic device of claim **10**, comprising an electrical component disposed over and electrically coupled to the first and second contact pads, wherein the component does not overlap the vias.

15. The electronic device of claim **10**, wherein the first via is coupled to a power supply, the second via is coupled to ground, and the component is a bypass capacitor.

16. The electronic device of claim **10**, wherein the electronic device comprises at least one of a computer, server, notebook, workstation, tablet PC, a mobile phone, and a smart phone.

17. A method comprising:
- forming a grid of vias in a circuit board, the grid of vias comprising a first via and a second via;
- forming a first contact pad electrically coupled to the first via at a first angle with respect to a reference line crossing through the center of the first and second vias; and
- forming a second contact pad electrically coupled to the second via on an opposite side of the reference line at a second angle with respect to the reference line, wherein a footprint that encompasses an area between the first and second contact pads does not cover the first and second vias.

18. The method of claim **17**, comprising coupling a bypass capacitor to the first and second contact pads, wherein the bypass capacitor does not overlap the vias when coupled to the first and second contact pads.

19. The method of claim **18**, wherein a center-to-center distance between the first and second vias is equal to or less than 0.8 millimeters and the electrical component is disposed between the first and second vias.

20. The method of claim **18**, wherein the first angle and the second angle are both less than 180 degrees.

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